











TS3A5017-Q1

SCDS387-OCTOBER 2018

# TS3A5017-Q1 2-Channel, 4:1, Analog Switch for Automotive Applications

#### **Features**

- AEC-Q100 Qualified for Automotive Applications
  - Device Temperature: –40°C to 125°C, T<sub>A</sub>
  - Device HBM Classification Level: ±1500-V
  - Device CDM Classification Level: ±1000-V
- Supports Powered-off Protection, I/O Pins Hi-Z When  $V_{CC} = 0V$
- Low ON-State Resistance
- Low Charge Injection
- 1  $\Omega$  ON-State Resistance Matching
- 0.25% Total Harmonic Distortion (THD+N)
- 2.3-V to 3.6-V Single-Supply Operation
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II

## **Applications**

- Sample-and-Hold Circuits
- Infotainment Audio and Video Signal Routing
- **Telematics Control Unit**

## 3 Description

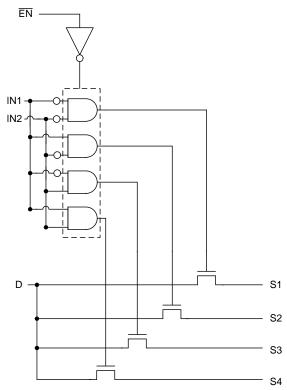
The TS3A5017-Q1 device is a 2-channel 4:1 multiplexer that is designed to operate from 2.3 V to 3.6 V. This device is bidirectional and can handle both digital and analog signals. The powered-off protection feature of this device ensures the signal path is high impedance when  $V_{CC} = 0 V$  which simplifies power sequencing and improves system reliability.

#### Device Information<sup>(1)</sup>

PART NUMBER	PACKAGE	BODY SIZE (NOM)			
TS3A5017-Q1	VQFN (16)	4.00 mm × 3.50 mm			

(1) For all available packages, see the orderable addendum at the end of the data sheet.

#### **Block Diagram**





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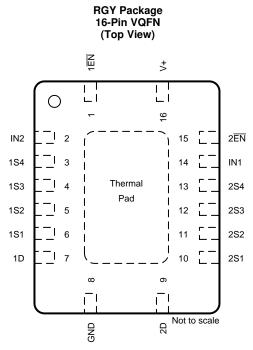
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# 4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

DATE	REVISION	NOTES
October 2018	*	Initial release

# 5 Pin Configuration and Functions



If exposed thermal pad is used, it must be connected as a secondary ground or left electrically open.

#### **Pin Functions**

PIN TYPE		TVDE	DESCRIPTION
NO.	NAME	ITPE	DESCRIPTION
7	1D	I/O	Common path for switch 1
1	1 <del>EN</del>	1	Active-low enable for switch 1
6	1S1	I/O	Switch 1 channel 1
5	1S2	I/O	Switch 1 channel 2
4	1S3	I/O	Switch 1 channel 3
3	1S4	I/O	Switch 1 channel 4
9	2D	I/O	Common path for switch 2
15	2EN	1	Active-low enable for switch 2
10	2S1	I/O	Switch 2 channel 1
11	2S2	I/O	Switch 2 channel 2
12	2S3	I/O	Switch 2 channel 3
13	2S4	I/O	Switch 2 channel 4
8	GND	-	Ground
14	IN1	I	Switch 1 input select
2	IN2	I	Switch 2 input select
16	V+	_	Supply voltage

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# TEXAS INSTRUMENTS

### 6 Specifications

#### 6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted) (1) (2)

			MIN	MAX	UNIT
V <sub>+</sub>	Supply voltage <sup>(3)</sup>		-0.5	4.6	٧
$V_S, V_D$	Analog voltage <sup>(3)</sup> (4)		-0.5	4.6	٧
I <sub>SK</sub> , I <sub>DK</sub>	Analog port clamp current	V <sub>S</sub> , V <sub>D</sub> < 0	-50		mA
$I_S$ , $I_D$	ON-state switch current	$V_S$ , $V_D = 0$ to 7 V	-128	128	mA
VI	Digital input voltage		-0.5	4.6	<b>V</b>
I <sub>IK</sub>	Digital input clamp current (3) (4)	V <sub>1</sub> < 0	-50		mA
I <sub>+</sub>	Continuous current through V <sub>+</sub>			100	mA
I <sub>GND</sub>	Continuous current through GND		-100		mA
T <sub>stg</sub>	Storage temperature		-65	150	°C

<sup>(1)</sup> Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to thedevice. These are stress ratings only, and functional operation of the device at these or any otherconditions beyond those indicated under Recommended OperatingConditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) The algebraic convention, whereby the most negative value is aminimum and the most positive value is a maximum.

(3) All voltages are with respect to ground, unless otherwisespecified.

### 6.2 ESD Ratings

			VALUE	UNIT
		Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 (1)	±1500	
V <sub>(ESD)</sub>	Electrostatic discharge	Charged-device model (CDM), per JEDEC specification JESD22-C101 (2)	±1000	V

<sup>(1)</sup> JEDEC document JEP155 states that 500-V HBM allows safemanufacturing with a standard ESD control process.

#### 6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	MAX	UNIT
$V_{I/O}$	Switch input/output voltage range	0	3.6	V
V+	Supply voltage range	2.3	3.6	V
VI	Control input voltage range	0	3.6	V
T <sub>A</sub>	Operating Temperature Range	-40	125	°C

#### 6.4 Thermal Information

		TS3A5017-Q1	
	THERMAL METRIC <sup>(1)</sup>		UNIT
		16 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	47.1	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	58.5	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	24.0	°C/W
ΨЈТ	Junction-to-top characterization parameter	1.8	°C/W
ΨЈВ	Junction-to-board characterization parameter	24.0	°C/W

(1) For more information about traditional and new thermalmetrics, see the IC Package ThermalMetrics application report.

<sup>(4)</sup> The input and output voltage ratings may be exceeded if theinput and output clamp-current ratings are observed.

<sup>(2)</sup> JEDEC document JEP157 states that 250-V CDM allows safemanufacturing with a standard ESD control process.



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# 6.5 Electrical Characteristics for 3.3-VSupply

 $V_{\perp} = 2.7 \text{ V}$  to 3.6 V,  $T_{\Delta} = -40 ^{\circ}\text{C}$  to 125 °C (unless otherwise noted) (1)

	PARAMETER		TEST CONDITIO	NS	MIN	TYP	MAX	UNIT	
Analog Swite	ch								
V <sub>D</sub> , V <sub>S</sub>	Analog signal range				0		$V_{\scriptscriptstyle +}$	V	
r <sub>on</sub>	ON-state	$0 \le V_S \le V_+$	Switch ON,	T <sub>A</sub> = 25°C V <sub>+</sub> = 3 V		11		Ω	
-011	resistance	$I_D = -32 \text{ mA},$	see Figure 12	$T_A = Full$ $V_+ = 3 V$			16		
$\Delta r_{on}$	ON-state resistance match	V <sub>S</sub> = 2.1 V,	Switch ON,	T <sub>A</sub> = 25°C V <sub>+</sub> = 3 V		1		Ω	
	between channels	$I_D = -32 \text{ mA},$	see Figure 12	$T_A = Full$ $V_+ = 3 V$			5		
r <sub>on(flat)</sub>	ON-state	$0 \le V_S \le V_+$	Switch ON,	T <sub>A</sub> = 25°C V <sub>+</sub> = 3 V		7		Ω	
	resistance flatness	I <sub>D</sub> = -32 mA,	see Figure 12	T <sub>A</sub> = Full V <sub>+</sub> = 3 V			12		
I <sub>S(OFF)</sub>		$V_S = 1 \ V, \ V_D = 3 \ V,$ or		T <sub>A</sub> = 25°C V <sub>+</sub> = 3.6 V		0.05			
	S OFF leakage	$V_S = 3 \text{ V}, V_D = 1 \text{ V},$ Switch OFF,	$T_A = \text{Full}$ $V_+ = 3.6 \text{ V}$	-0.3		0.3	μΑ		
I <sub>SPWR(OFF)</sub>	current WR(OFF)	current $V_S = 0$ to 3.6 V,	$V_S = 0 \text{ to } 3.6 \text{ V},$ $V_D = 3.6 \text{ V to } 0,$	see Figure 13	T <sub>A</sub> = 25°C V <sub>+</sub> = 0 V		0.5		μ.
-		ν <sub>U</sub> = 0.0 ν ιο υ,		$T_A = \text{Full}$ $V_+ = 0 \text{ V}$ $T = 25^{\circ}\text{C}$	-10		10		
I <sub>D(OFF)</sub>		$V_S = 1 V$ , $V_D = 3 V$ , or		$T_A = 25^{\circ}C$ $V_+ = 3.6 \text{ V}$ $T_A = \text{Full}$		0.05			
	D OFF leakage current	$V_S = 3 V, V_D = 1 V,$	Switch OFF, see Figure 13	$V_{+} = 3.6 \text{ V}$ $T_{A} = 25^{\circ}\text{C}$	-0.3		0.3	μΑ	
I <sub>DPWR(OFF)</sub>		$V_D = 0 \text{ to } 3.6 \text{ V},$ $V_S = 3.6 \text{ V to } 0,$	coo rigulo ro	$V_{+} = 0 V$ $T_{A} = Full$		0.5		Ī	
		V <sub>S</sub> = 1 V, V <sub>D</sub> =		$V_{+} = 0 \text{ V}$ $T_{A} = 25^{\circ}\text{C}$	-20		20		
I <sub>S(ON)</sub>	S ON leakage	Open, or	Switch ON,	V <sub>+</sub> = 3.6 V		0.05		μΑ	
	current	$V_S = 3 V, V_D =$ Open,	see Figure 14	$T_A = Full$ $V_+ = 3.6 V$	-0.3		0.3		
Invovi	D ON leakage	$V_D = 1 V, V_S =$ Open, or	Switch ON,	$T_A = 25^{\circ}C$ $V_+ = 3.6 \text{ V}$		0.05		μΑ	
I <sub>D(ON)</sub>	current	$V_D = 3 V, V_S =$ Open,	see Figure 14	$T_A = Full$ $V_+ = 3.6 V$	-0.3		0.3	μΛ	
	rol Inputs (IN1, IN2, EN)(2)						1		
V <sub>IH</sub>	Input logic high			T <sub>A</sub> = Full	2		$V_{+}$	V	
V <sub>IL</sub>	Input logic low			T <sub>A</sub> = Full	0		0.8	V	
I <sub>IH</sub> , I <sub>IL</sub>	Input leakage	$V_I = V_+ \text{ or } 0$		T <sub>A</sub> = 25°C V <sub>+</sub> = 3.6 V		0.05		μΑ	
	current			$T_A = Full$ $V_+ = 3.6 V$	-1		1	-	
Q <sub>C</sub>	Charge injection	$V_{GEN} = 0$ , $R_{GEN} = 0$ , $C_L = 0.1$ nF,	See Figure 21	T <sub>A</sub> = 25°C V <sub>+</sub> = 3.3 V		5		pC	
C <sub>S(OFF)</sub>	S OFF capacitance	$V_S = V_+ \text{ or GND},$ Switch OFF,	See Figure 15	T <sub>A</sub> = 25°C V <sub>+</sub> = 3.3 V		4.5		pF	
C <sub>D(OFF)</sub>	D OFF capacitance	V <sub>D</sub> = V <sub>+</sub> or GND, Switch OFF,	See Figure 15	T <sub>A</sub> = 25°C V <sub>+</sub> = 3.3 V		19		pF	
C <sub>S(ON)</sub>	S ON capacitance	$V_S = V_+ \text{ or GND},$ Switch ON,	See Figure 15	$T_A = 25^{\circ}C$ $V_+ = 3.3 \text{ V}$		27		pF	

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 <sup>(1)</sup> The algebraic convention, whereby the most negative value is aminimum and the most positive value is a maximum
 (2) All unused digital inputs of the device must be held atV<sub>+</sub> or GND to ensure proper device operation. Refer to the TI applicationreport, Implications of Slow or Floating CMOS Inputs, literaturenumber SCBA004.

## **Electrical Characteristics for 3.3-VSupply (continued)**

 $V_{+} = 2.7 \text{ V to } 3.6 \text{ V}, T_{A} = -40^{\circ}\text{C to} 125^{\circ}\text{C (unless otherwise noted)}^{(1)}$ 

	PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
C <sub>D(ON)</sub>	D ON capacitance	$V_D = V_+ \text{ or GND},$ Switch ON,	See Figure 15	T <sub>A</sub> = 25°C V <sub>+</sub> = 3.3 V		27		pF
Cı	Digital input capacitance	$V_I = V_+ \text{ or GND},$	See Figure 15	T <sub>A</sub> = 25°C V <sub>+</sub> = 3.3 V		3		pF
BW	Bandwidth	$R_L = 50 \Omega$ , Switch ON,	See Figure 17	T <sub>A</sub> = 25°C V <sub>+</sub> = 3.3 V		165		MHz
O <sub>ISO</sub>	OFF isolation	$R_L = 50 \Omega$ , f = 1 MHz,	See Figure 18	T <sub>A</sub> = 25°C V <sub>+</sub> = 3.3 V		-69		dB
O <sub>ISO</sub>	OFF isolation	$R_L = 50 \Omega$ , f = 10 MHz,	See Figure 18	T <sub>A</sub> = 25°C V <sub>+</sub> = 3.3 V		-49		dB
X <sub>TALK</sub>	Crosstalk	$R_L = 50 \ \Omega,$ $f = 1 \ MHz,$	See Figure 19	T <sub>A</sub> = 25°C V <sub>+</sub> = 3.3 V		-69		dB
$X_{TALK(ADJ)}$	Crosstalk adjacent	$R_L = 50 \ \Omega,$ $f = 1 \ MHz,$	See Figure 20	T <sub>A</sub> = 25°C V <sub>+</sub> = 3.3 V		-80		dB
THD	Total harmonic distortion	$R_L = 600 \ \Omega,$ $C_L = 50 \ pF,$	f = 20 Hz to 20 kHz, see Figure 22	T <sub>A</sub> = 25°C V <sub>+</sub> = 3.3 V		0.25		%
Supply								
X <sub>TALK(ADJ)</sub>	Positive supply	$V_1 = V_+$ or GND.	Switch ON or OFF	T <sub>A</sub> = 25°C V <sub>+</sub> = 3.6 V		2.5	7	4
1+	current	v <sub>I</sub> = v <sub>+</sub> or GND,	SWILCTI ON OF OFF	$T_A = Full$ $V_+ = 3.6 V$		·	10	μΑ

## 6.6 Electrical Characteristics for 2.5-VSupply

 $V_{+} = 2.3 \text{ V to } 2.7 \text{ V}, T_{A} = -40 ^{\circ}\text{C to} 125 ^{\circ}\text{C (unless otherwise noted)}^{(1)}$ 

PA	ARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT	
Analog Swi	itch								
$V_D, V_S$	Analog signal range				0		٧+	٧	
r <sub>on</sub>	ON-state	$0 \le V_S \le V_+$	Switch ON,	T <sub>A</sub> = 25°C V <sub>+</sub> = 2.3 V		22		Ω	
	resistance	$I_D = -24 \text{ mA},$	see Figure 12	$T_A = Full$ $V_+ = 2.3 V$			28	Ω	
	ON-state resistance match between channels	$V_{c} = 1.6 \text{ V}$	V <sub>S</sub> = 1.6 V,	T <sub>A</sub> = 2	T <sub>A</sub> = 25°C V <sub>+</sub> = 2.3 V		1		
∆r <sub>on</sub>		$I_D = -24 \text{ mA},$	see Figure 12	$T_A = Full$ $V_+ = 2.3 V$			5	Ω	
_	ON-state resistance flatness	5 7,	Switch ON, see Figure 12	T <sub>A</sub> = 25°C V <sub>+</sub> = 2.3 V		18		Ω	
r <sub>on(flat)</sub>				$T_A = Full$ $V_+ = 2.3 V$			24	12	
		$V_S = 0.5 \text{ V}, V_D = 2.2 \text{ V},$		T <sub>A</sub> = 25°C V <sub>+</sub> = 2.7 V		0.05			
I <sub>S(OFF)</sub>	OFF leakage current V <sub>S</sub> =	$V_S = 2.2 \text{ V}, V_D = 0.5 \text{ V},$	- ·	Switch OFF,	$T_A = Full$ $V_+ = 2.7 V$	-0.3		0.3	
I <sub>SPWR(OFF)</sub>		See Floure 15	see Figure 13	$T_A = 25^{\circ}C$ $V_+ = 0 \text{ V}$		0.5		μΑ	
			$T_A = Full$ $V_+ = 0 V$	-15		15			

(1) The algebraic convention, whereby the most negative value is aminimum and the most positive value is a maximum



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# **Electrical Characteristics for 2.5-VSupply (continued)**

 $V_{+} = 2.3 \text{ V to } 2.7 \text{ V}, T_{A} = -40 ^{\circ}\text{C to} 125 ^{\circ}\text{C (unless otherwise noted)}^{(1)}$ 

P	ARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$I_{D(OFF)}$	D	$\begin{aligned} &V_S = 0.5 \text{ V}, \ V_D = 2.2 \text{ V}, \\ &\text{or} \\ &V_S = 2.2 \text{ V}, \ V_D = 0.5 \text{V}, \end{aligned}$	Switch OFF,	$T_A = 25^{\circ}C$ $V_+ = 2.7 V$ $T_A = Full$ $V_+ = 2.7 V$	-0.3	0.05	0.3	
I <sub>DPWR(OFF)</sub>	OFF leakage current	$V_D = 0 \text{ to } 2.7 \text{ V},$	see Figure 13	T <sub>A</sub> = 25°C V <sub>+</sub> = 0 V		0.5		μΑ
		$V_S = 2.7 \text{ V to } 0,$		$T_A = Full$ $V_+ = 0 V$	-20		20	
I <sub>S(ON)</sub>	S ON leakage	$V_S = 0.5 \text{ V}, V_D = \text{Open},$ or	Switch ON,	$T_A = 25^{\circ}C$ $V_+ = 2.7 \text{ V}$		0.05		μА
0(011)	current	$V_S = 2.2 \text{ V}, V_D = \text{Open},$	see Figure 14	$T_A = Full$ $V_+ = 2.7 V$	-0.3		0.3	•
I <sub>D(ON)</sub>	D ON leakage	$V_D = 0.5 \text{ V}, V_S = \text{Open},$	Switch ON,	$T_A = 25^{\circ}C$ $V_+ = 2.7 \text{ V}$		0.05		μА
current	current	$V_D = 2.2 \text{ V}, V_S = \text{Open},$	see Figure 14	$T_A = Full$ $V_+ = 2.7 V$	-0.3		0.3	μ.
Logic Input	ts (IN1, IN2, <del>EN</del> ) <sup>(2)</sup>							
V <sub>IH</sub>	Input logic high			$T_A = Full$	1.7		$V_{+}$	V
$V_{IL}$	Input logic low			$T_A = Full$	0		0.7	V
	Input leakage current	V V 27 0		T <sub>A</sub> = 25°C V <sub>+</sub> = 2.7 V		0.05		^
I <sub>IH</sub> , I <sub>IL</sub>		$V_1 = V_+ \text{ or } 0$		$T_A = Full$ $V_+ = 2.7 V$	-1		1	μΑ
Q <sub>C</sub>	Charge injection	$\begin{split} &V_{GEN}=0,R_{GEN}=0,\\ &C_L=0.1\;nF, \end{split}$	See Figure 21	$T_A = Full$ $V_+ = 2.5 V$		3		pC
C <sub>S(OFF)</sub>	S OFF capacitance	$V_S = V_+ \text{ or GND},$ Switch OFF,	See Figure 15	$T_A = Full$ $V_+ = 2.5 V$		4.5		pF
$C_{D(OFF)}$	D OFF capacitance	$V_D = V_+ \text{ or GND},$ Switch OFF,	See Figure 15	$T_A = Full$ $V_+ = 2.5 V$		18.5		pF
C <sub>S(ON)</sub>	S ON capacitance	$V_S = V_+ \text{ or GND},$ Switch ON,	See Figure 15	$T_A = Full$ $V_+ = 2.5 V$		26		pF
$C_{D(ON)}$	D ON capacitance	$V_D = V_+$ or GND, Switch ON,	See Figure 15	$T_A = Full$ $V_+ = 2.5 V$		26		pF
C <sub>I</sub>	Digital input capacitance	$V_I = V_+ \text{ or GND},$	See Figure 15	$T_A = Full$ $V_+ = 2.5 V$		3		pF
BW	Bandwidth	$R_L = 50 \Omega$ , Switch ON,	See Figure 17	$T_A = Full$ $V_+ = 2.5 V$		165		MHz
O <sub>ISO</sub>	OFF isolation	$R_L = 50 \Omega,$ f = 1 MHz,	See Figure 18	$T_A = Full$ $V_+ = 2.5 V$		-69		dB
O <sub>ISO</sub>	OFF isolation	$R_L = 50 \Omega,$ f = 10 MHz,	See Figure 18	$T_A = Full$ $V_+ = 2.5 V$		-49		dB
X <sub>TALK</sub>	Crosstalk	$R_L = 50 \ \Omega,$ $f = 1 \ MHz,$	See Figure 19	$T_A = Full$ $V_+ = 2.5 V$		-69		dB
X <sub>TALK(ADJ)</sub>	Crosstalk adjacent	$R_L = 50 \Omega,$ f = 1 MHz,	See Figure 20	$T_A = Full$ $V_+ = 2.5 V$		-85		dB
THD	Total harmonic distortion	$R_L = 600 \Omega,$ $C_L = 50 pF,$	f = 20 Hz to 20 kHz, see Figure 22	$T_A = Full$ $V_+ = 2.5 V$		0.3		%

<sup>(2)</sup> All unused digital inputs of the device must be held atV<sub>+</sub> or GND to ensure proper device operation. Refer to the TI applicationreport, *Implications of Slow or Floating CMOS Inputs*, literaturenumber SCBA004.

# TEXAS INSTRUMENTS

## **Electrical Characteristics for 2.5-VSupply (continued)**

 $V_{+} = 2.3 \text{ V to } 2.7 \text{ V}, T_{A} = -40^{\circ}\text{C to} 125^{\circ}\text{C (unless otherwise noted)}^{(1)}$ 

PAI	PARAMETER TEST CONDITIONS							UNIT
-	Positive supply	V V or CND	Cuitale ON au OFF	$T_A = Full$ $V_+ = 2.7 V$		2.5	7	^
I <sub>+</sub>	current	$V_1 = V_+ \text{ or GND},$	Switch ON or OFF	$T_A = Full$ $V_+ = 2.7 V$			10	μА

## 6.7 Switching Characteristics for 3.3-VSupply

over operating free-air temperature range (unless otherwise noted)

P	ARAMETER	TI	MIN	TYP	MAX	UNIT			
	Turnon time <sup>(1)</sup>	$V_D = 2 V$ , $C_L = 35 pF$ ,		T <sub>A</sub> = 25°C V <sub>+</sub> = 3.3 V		5	9.5		
t <sub>ON</sub>	Turnon time (*)	$R_L = 300 \Omega$ ,	see Figure 16	$T_A = Full$ $V_+ = 3 V \text{ to } 3.6 V$			10.5	ns	
	Turnoff time <sup>(1)</sup>	Turnoff time (1) $V_D = 2 V$ ,	$V_D = 2 V$ , $R_L = 300 \Omega$ ,	C <sub>L</sub> = 35 pF,	T <sub>A</sub> = 25°C V <sub>+</sub> = 3.3 V		1.5	3.5	ns
t <sub>OFF</sub>		$R_L = 300 \Omega$ ,	see Figure 16	$T_A = Full$ $V_+ = 3 V \text{ to } 3.6 V$			4.5	115	

<sup>(1)</sup> Specified by design, not tested in production

## 6.8 Switching Characteristics for 2.5-VSupply

over operating free-air temperature range (unless otherwise noted)

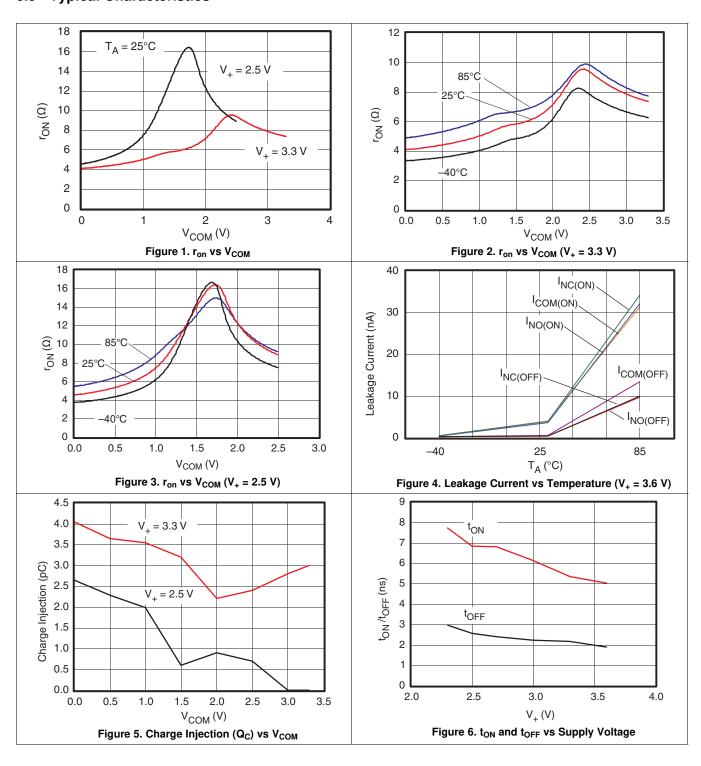
PARA	METER			MIN	TYP	MAX	UNIT	
	T (1)	V <sub>COM</sub> = 2 V,	C <sub>L</sub> = 35 pF,	T <sub>A</sub> = 25°C V <sub>+</sub> = 2.5 V		5	8	
t <sub>ON</sub>	Turnon time <sup>(1)</sup>	$\begin{aligned} &V_{COM} = 2 \ V, \\ &R_L = 300 \ \Omega, \end{aligned}$	see Figure 16	$T_A = Full$ V <sub>+</sub> = 2.3 V to 2.7 V			10	ns
	T (1)	V <sub>COM</sub> =2 V,	C <sub>L</sub> = 35 pF,	T <sub>A</sub> = 25°C V <sub>+</sub> = 2.5 V		2	4.5	
toff	Turnoff time <sup>(1)</sup>	$V_{COM} = 2 V,$ $R_L = 300 \Omega,$	see Figure 16	$T_A = Full$ V <sub>+</sub> = 2.3 V to 2.7 V			6	ns

(1) Specified by design, not tested in production.



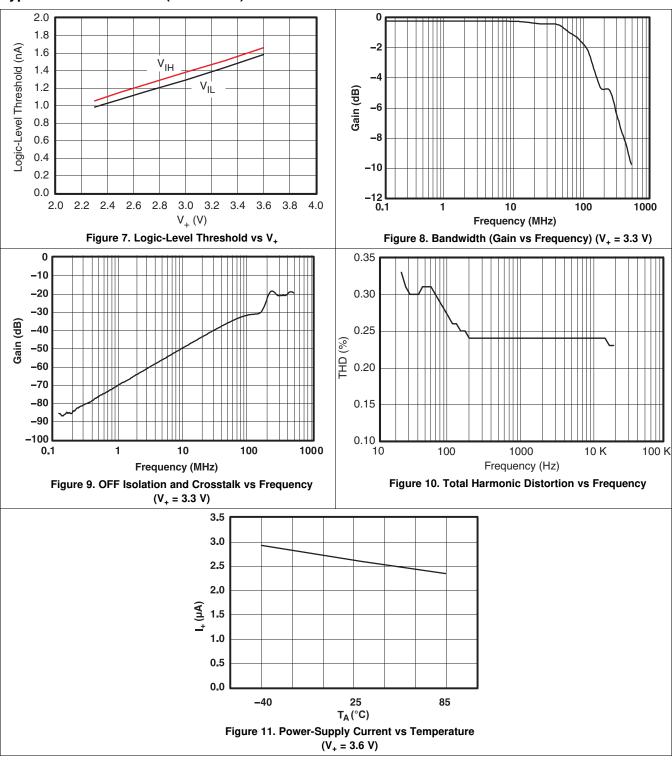
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## 6.9 Typical Characteristics



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## **Typical Characteristics (continued)**



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## 7 Parameter Measurement Information

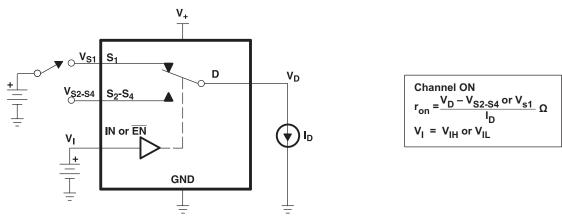


Figure 12. ON-State Resistance (ron)

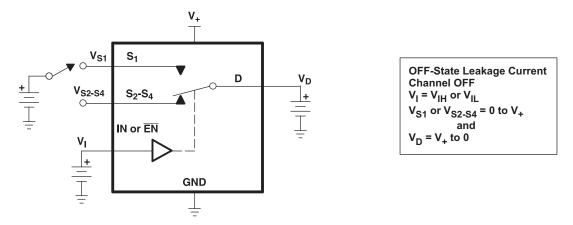


Figure 13. OFF-State Leakage Current ( $I_{D(OFF)}$ ,  $I_{S(OFF)}$ )

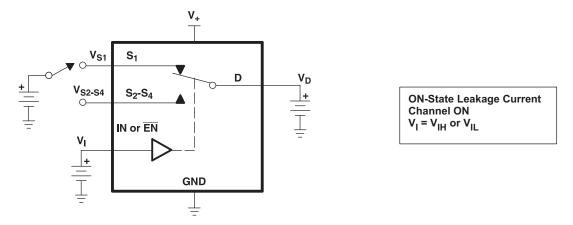
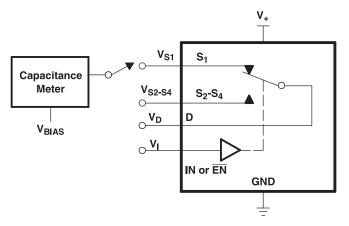


Figure 14. ON-State Leakage Current (I<sub>D(ON)</sub>, I<sub>S(ON)</sub>)

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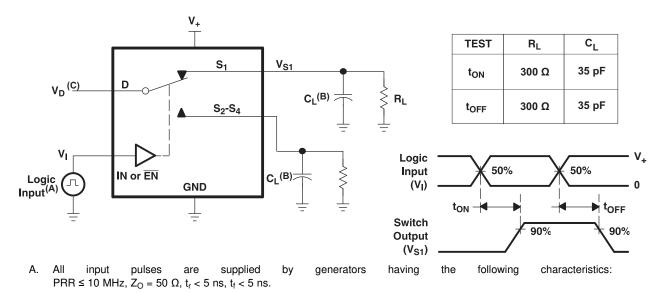
#### **Parameter Measurement Information (continued)**



 $V_{BIAS} = V_{+}$  to GND  $V_{I} = V_{IH}$  or  $V_{IL}$ 

Capacitance is measured at S1, S2-S4, D, and IN inputs during ON and OFF conditions.

Figure 15. Capacitance (C<sub>I</sub>,  $C_{D(OFF)}$ ,  $C_{D(ON)}$ ,  $C_{S(OFF)}$ ,  $C_{S(ON)}$ )



- B. C<sub>L</sub> includes probe and jig capacitance.
- C. See Electrical Characteristics for V<sub>D</sub>.

Figure 16. Turnon (t<sub>ON</sub>) and Turnoff Time (t<sub>OFF</sub>)

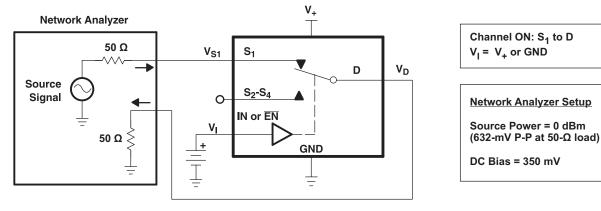
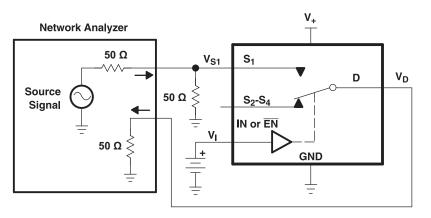


Figure 17. Bandwidth (BW)



#### **Parameter Measurement Information (continued)**



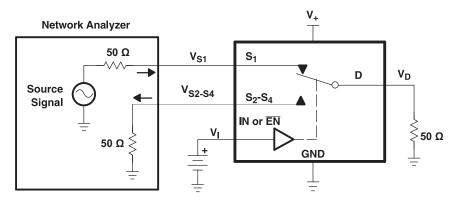
Channel OFF: S to D V<sub>I</sub> = V<sub>+</sub> or GND

**Network Analyzer Setup** 

Source Power = 0 dBm (632-mV P-P at 50-Ω load)

DC Bias = 350 mV

Figure 18. OFF Isolation (O<sub>ISO</sub>)



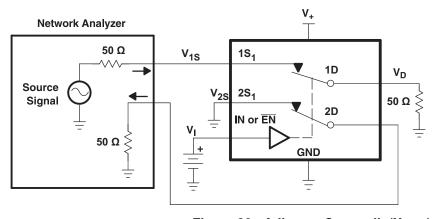
Channel ON:  $S_1$  to D Channel OFF:  $S_2$ - $S_4$  to D  $V_1 = V_+$  or GND

**Network Analyzer Setup** 

Source Power = 0 dBm (632-mV P-P at 50-Ω load)

DC Bias = 350 mV

Figure 19. Crosstalk (X<sub>TALK</sub>)



Channel ON: S<sub>1</sub> to D

**Network Analyzer Setup** 

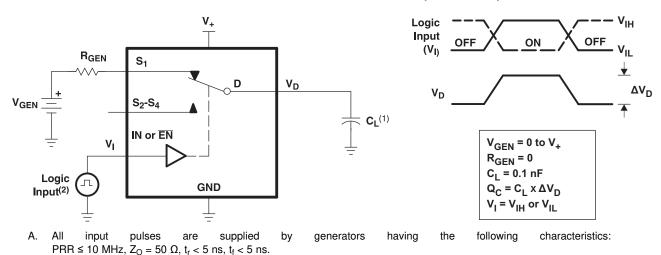
Source Power = 0 dBm (632-mV P-P at 50-Ω load)

DC Bias = 350 mV

Figure 20. Adjacent Crosstalk (X<sub>TALK</sub>)

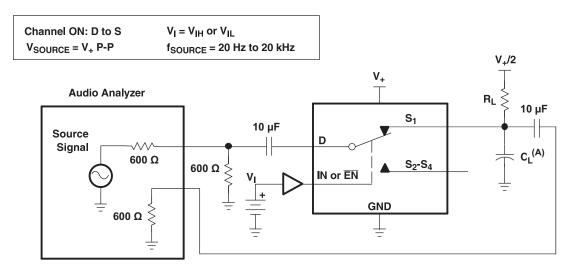


## **Parameter Measurement Information (continued)**



B. C<sub>L</sub> includes probe and jig capacitance.

Figure 21. Charge Injection (Q<sub>C</sub>)



A. C<sub>L</sub> includes probe and jig capacitance.

Figure 22. Total Harmonic Distortion (THD)

# 8 Detailed Description

#### 8.1 Overview

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The TS3A5017-Q1 is a dual Single-Pole-4-Throw (SP4T) solid-state analog switch. The TS3A5017-Q1, like all analog switches, is bidirectional. Each D pin connects to its four respective S pins, with the switch connection dependent on the status of EN, IN2, and IN1. See Table 1 for the switch configuration truth table.

#### 8.2 Functional Block Diagram

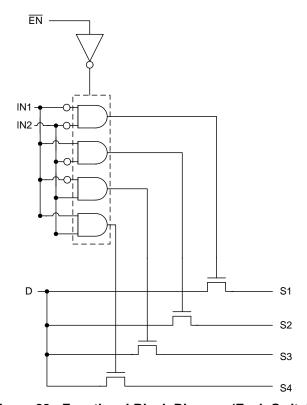


Figure 23. Functional Block Diagram (Each Switch)

#### 8.3 Feature Description

Isolation in powered-down mode allows signals to be present at the inputs while the switch is powered off without causing damage to the device. The low ON-state resistance and low charge injection give the TS3A5017-Q1 better performance at higher speeds.

#### 8.4 Device Functional Modes

**Table 1. Function Table** 

ĒN	IN2	IN1	D TO S, S TO D
L	L	L	$D = S_1$
L	L	Н	$D = S_2$
L	Н	L	$D = S_3$
L	Н	Н	D = S <sub>4</sub>
Н	Х	Х	OFF

# TEXAS INSTRUMENTS

### 9 Application and Implementation

#### NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

#### 9.1 Application Information

The TS3A5017-Q1 can be used in a variety of customer systems. The TS3A5017-Q1 can be used anywhere multiple analog or digital signals must be selected to pass across a single line.

### 9.2 Typical Application

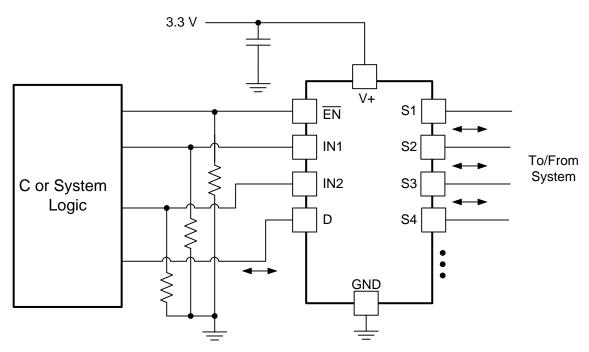


Figure 24. System Schematic for TS3A5017-Q1

#### 9.2.1 Design Requirements

In this particular application, V+ was 3.3 V, although V+ is allowed to be any voltage specified in *Recommended Operating Conditions*. A decoupling capacitor is recommended on the V+ pin. See *Power Supply Recommendations* for more details.

#### 9.2.2 Detailed Design Procedure

In this application,  $\overline{\text{EN}}$ , IN1, and IN2 are, by default, pulled low to GND. Choose these resistor sizes based on the current driving strength of the GPIO, the desired power consumption, and the switching frequency (if applicable). If the GPIO is open-drain, use pullup resistors instead.

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### **Typical Application (continued)**

#### 9.2.3 Application Curve

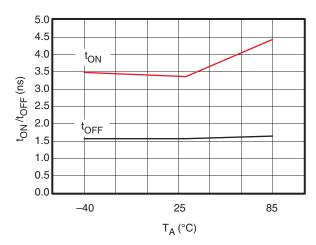


Figure 25.  $t_{ON}$  and  $t_{OFF}$  vs Temperature (V<sub>+</sub> = 3.3 V)

## 10 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the Recommended Operation Conditions.

Each  $V_{CC}$  terminal should have a good bypass capacitor to prevent power disturbance. For devices with a single supply, a 0.1- $\mu F$  bypass capacitor is recommended. If there are multiple pins labeled  $V_{CC}$ , then a 0.01- $\mu F$  or 0.022- $\mu F$  capacitor is recommended for each  $V_{CC}$  because the  $V_{CC}$  pins will be tied together internally. For devices with dual-supply pins operating at different voltages, for example  $V_{CC}$  and  $V_{DD}$ , a 0.1- $\mu F$  bypass capacitor is recommended for each supply pin. It is acceptable to parallel multiple bypass capacitors to reject different frequencies of noise. 0.1- $\mu F$  and 1- $\mu F$  capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results.

# TEXAS INSTRUMENTS

### 11 Layout

#### 11.1 Layout Guidelines

Reflections and matching are closely related to loop antenna theory, but different enough to warrant their own discussion. When a PCB trace turns a corner at a 90° angle, a reflection can occur. This is primarily due to the change of width of the trace. At the apex of the turn, the trace width is increased to 1.414 times its width. This upsets the transmission line characteristics, especially the distributed capacitance and self–inductance of the trace — resulting in the reflection. It is a given that not all PCB traces can be straight, and the traces will turn corners. Figure 26 shows progressively better techniques of rounding corners. Only the last example maintains constant trace width and minimizes reflections.

<u>Un</u>used switch I/Os, such as NO, NC, and COM, can be left floating or tied to GND. However, the IN1, IN2, and  $\overline{\text{EN}}$  pins must be driven high or low. Due to partial transistor turnon when control inputs are at threshold levels, floating control inputs can cause increased I<sub>CC</sub> or unknown switch selection states. See *Implications of Slow or Floating CMOS Inputs*, SCBA004 for more details.

#### 11.2 Layout Example

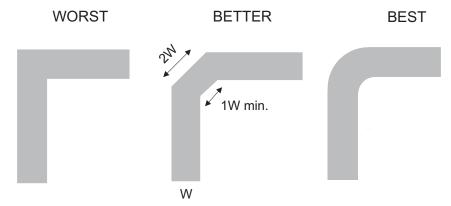


Figure 26. Trace Example

S Subm



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# 12 Device and Documentation Support

# 12.1 Device Support

#### 12.1.1 Device Nomenclature

**Table 2. Parameter Description** 

V <sub>COM</sub> V	
	/oltage at COM
V <sub>NC</sub> V	/oltage at NC
V <sub>NO</sub> V	/oltage at NO
r <sub>on</sub> R	Resistance between COM and NC or NO ports when the channel is ON
$\Delta r_{\sf on}$ D	Difference of r <sub>on</sub> between channels in a specific device
r <sub>on(flat)</sub> D	Difference between the maximum and minimum value of ron in a channel over the specified range of conditions
I <sub>NC(OFF)</sub> Lo	eakage current measured at the NC port, with the corresponding channel (NC to COM) in the OFF state
	Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the ON state and the output COM) open
I <sub>NO(OFF)</sub> Lo	eakage current measured at the NO port, with the corresponding channel (NO to COM) in the OFF state
	Leakage current measured at the NO port, with the corresponding channel (NO to COM) in the ON state and the output COM) open
I <sub>COM(OFF)</sub> L	eakage current measured at the COM port, with the corresponding channel (COM to NC or NO) in the OFF state
	Leakage current measured at the COM port, with the corresponding channel (COM to NC or NO) in the ON state and the output (NC or NO) open
V <sub>IH</sub> N	Minimum input voltage for logic high for the control input (IN, $\overline{\text{EN}}$ )
V <sub>IL</sub> N	Maximum input voltage for logic low for the control input (IN, $\overline{\sf EN}$ )
V <sub>I</sub> V	/oltage at the control input (IN, $\overline{\text{EN}}$ )
I <sub>IH</sub> , I <sub>IL</sub> Lo	eakage current measured at the control input (IN, EN)
	Furnon time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog output NC or NO) signal when the switch is turning ON.
t <sub>OFF</sub> T	Furnoff time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog output (NC or NO) signal when the switch is turning OFF.
Q <sub>C</sub> or	Charge injection is a measurement of unwanted signal coupling from the control (IN) input to the analog (NC or NO) output. This is measured in coulomb (C) and measured by the total charge induced due to switching of the control input. Charge injection, $Q_C = C_L \times \Delta V_{COM}$ , $C_L$ is the load capacitance and $\Delta V_{COM}$ is the change in analog output voltage.
C <sub>NC(OFF)</sub> C	Capacitance at the NC port when the corresponding channel (NC to COM) is OFF
	Capacitance at the NC port when the corresponding channel (NC to COM) is ON
	Capacitance at the NC port when the corresponding channel (NO to COM) is OFF
C <sub>NO(ON)</sub> C	Capacitance at the NC port when the corresponding channel (NO to COM) is ON
C <sub>COM(OFF)</sub> C	Capacitance at the COM port when the corresponding channel (COM to NC) is OFF
C <sub>COM(ON)</sub> C	Capacitance at the COM port when the corresponding channel (COM to NC) is ON
C <sub>I</sub> C	Capacitance of control input (IN, EN)
	DFF isolation of the switch is a measurement of OFF-state switch impedance. This is measured in dB in a specific requency, with the corresponding channel (NC to COM) in the OFF state.
X <sub>TALK</sub> ci	Crosstalk is a measurement of unwanted signal coupling from an ON channel to an OFF channel (NC1 to NO1). Adjacent crosstalk is a measure of unwanted signal coupling from an ON channel to an adjacent ON channel (NC1 to NC2). This is measured in a specific frequency and in dB.
BW B	Bandwidth of the switch. This is the frequency in which the gain of an ON channel is -3 dB below the DC gain.
THD m	Total harmonic distortion describes the signal distortion caused by the analog switch. This is defined as the ratio of root nean square (RMS) value of the second, third, and higher harmonic to the absolute magnitude of the fundamental narmonic.

# TEXAS INSTRUMENTS

#### 12.2 Documentation Support

#### 12.2.1 Related Documentation

Implications of Slow or Floating CMOS Inputs, SCBA004

#### 12.3 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on *Alert me* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

#### 12.4 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™ Online Community TI's Engineer-to-Engineer (E2E) Community. Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

**Design Support** *TI's Design Support* Quickly find helpful E2E forums along with design support tools and contact information for technical support.

#### 12.5 Trademarks

E2E is a trademark of Texas Instruments.

#### 12.6 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

#### 12.7 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

#### 13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

20







10-Dec-2020

#### PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
TS3A5017QRGYRQ1	ACTIVE	VQFN	RGY	16	3000	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	5017Q	Samples

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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#### OTHER QUALIFIED VERSIONS OF TS3A5017-Q1:



## **PACKAGE OPTION ADDENDUM**

10-Dec-2020

• Catalog: TS3A5017

NOTE: Qualified Version Definitions:

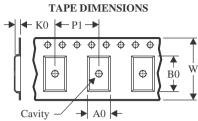
• Catalog - TI's standard catalog product

# **PACKAGE MATERIALS INFORMATION**

www.ti.com 3-Jun-2022

#### TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

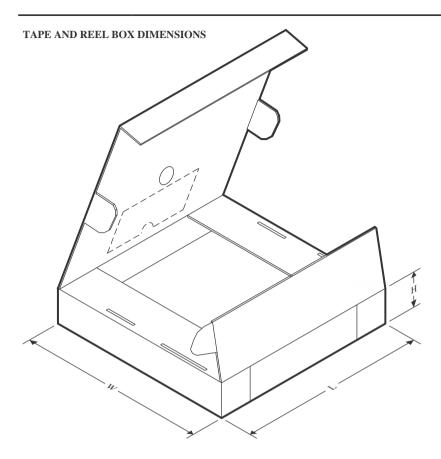


#### \*All dimensions are nominal

	Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
ĺ	TS3A5017QRGYRQ1	VQFN	RGY	16	3000	330.0	12.4	3.8	4.3	1.5	8.0	12.0	Q1

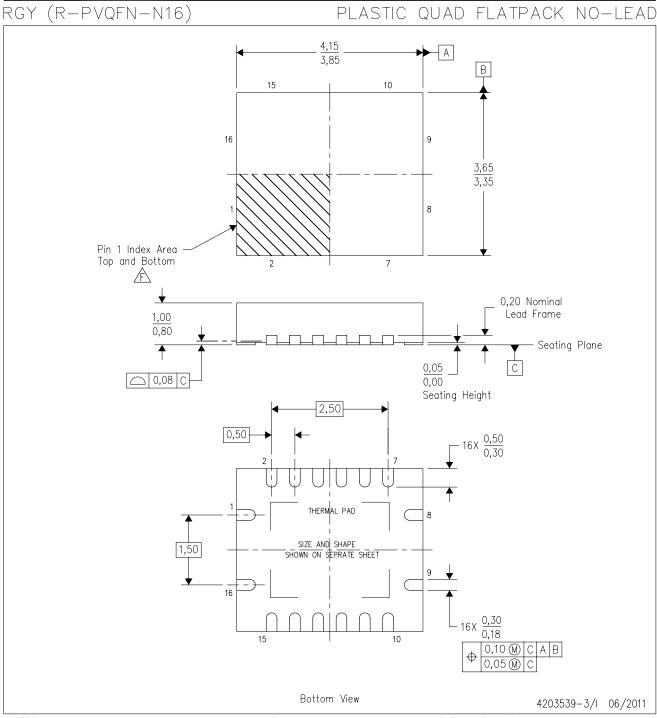
# **PACKAGE MATERIALS INFORMATION**

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#### \*All dimensions are nominal

Device	Device Package Type		Pins	SPQ	Length (mm)	Width (mm)	Height (mm)	
TS3A5017QRGYRQ1	VQFN	RGY	16	3000	367.0	367.0	35.0	



NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. QFN (Quad Flatpack No-Lead) package configuration.
- D. The package thermal pad must be soldered to the board for thermal and mechanical performance.
- E. See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions.
- Pin 1 identifiers are located on both top and bottom of the package and within the zone indicated. The Pin 1 identifiers are either a molded, marked, or metal feature.
- G. Package complies to JEDEC MO-241 variation BA.



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